

GENERAL DESCRIPTION

The ME4835 is the P-Channel logic enhancement mode power field effect transistors are produced using high cell density , DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits where high-side switching and low in-line power loss are needed in a very small outline surface mount package.

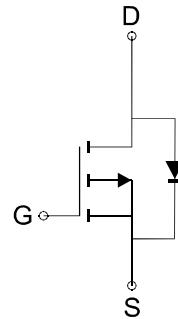
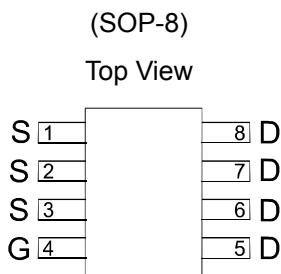
FEATURES

- $R_{DS(ON)} \leq 20m\Omega @ V_{GS} = -10V$
- $R_{DS(ON)} \leq 35m\Omega @ V_{GS} = -4.5V$
- Super high density cell design for extremely low $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

APPLICATIONS

- Power Management in Note book
- Portable Equipment
- Battery Powered System
- DC/DC Converter
- Load Switch
- DSC
- LCD Display inverter

PIN CONFIGURATION



P-Channel MOSFET

Absolute Maximum Ratings ($T_A=25^\circ C$ Unless Otherwise Noted)

Parameter		Symbol	10 secs	Steady State	Unit
Drain-Source Voltage		V_{DSS}	-30		V
Gate-Source Voltage		V_{GSS}	± 20		V
Continuous Drain Current($T_j=150^\circ C$)	$T_A=25^\circ C$	I_D	-9.1	-7	A
	$T_A=70^\circ C$		-7.3	-5.6	
Pulsed Drain Current		I_{DM}	-30		A
Avalanche Energy with Single Pulse($L=0.1mH$)		EAS	50		mJ
Continuous Source Current (Diode Conduction)		I_S	-2.1	-1.25	A
Maximum Power Dissipation	$T_A=25^\circ C$	P_D	2.5	1.5	W
	$T_A=70^\circ C$		1.6	0.9	
Operating Junction Temperature		T_J	-55 to 150		°C
Thermal Resistance-Junction to Ambient*		$R_{\theta JA}$	$T \leq 10 \text{ sec}$	30	°C/W
			Steady State	62	
Thermal Resistance-Junction to Case		$R_{\theta JC}$	38		°C/W

*The device mounted on 1in² FR4 board with 2 oz copper

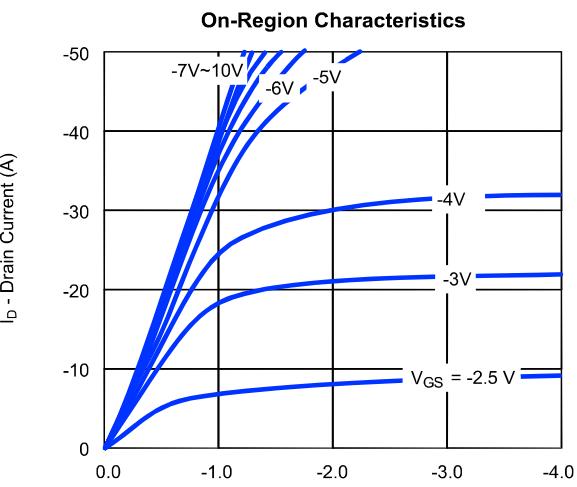
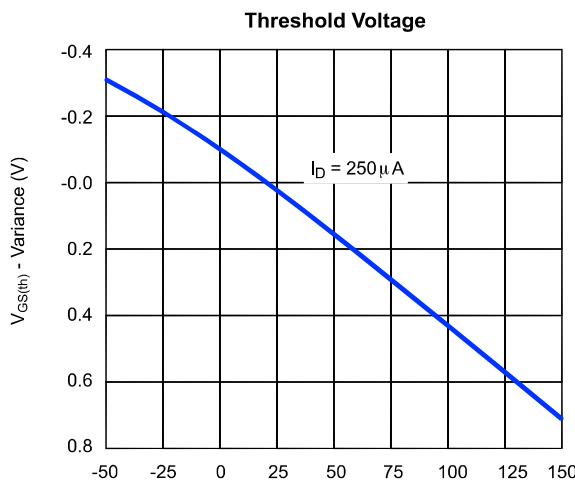
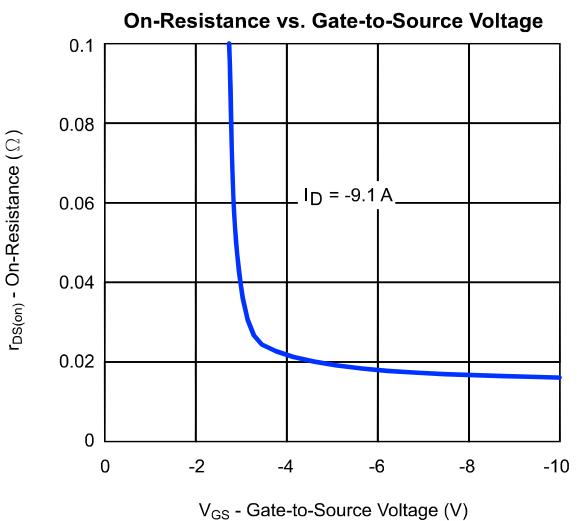
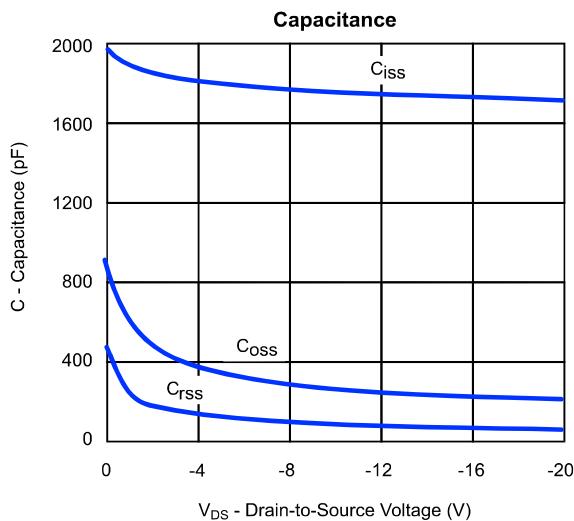
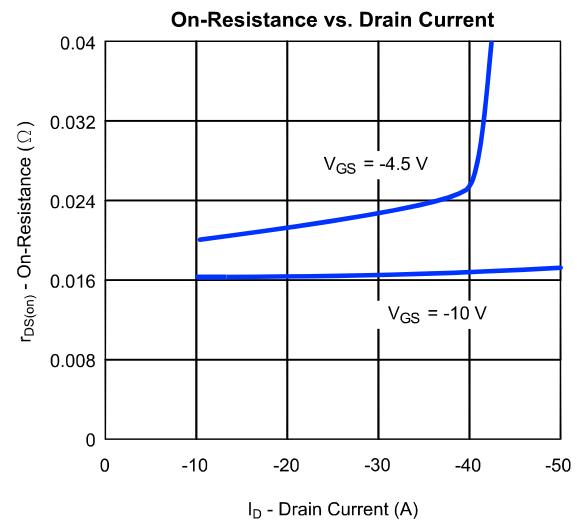
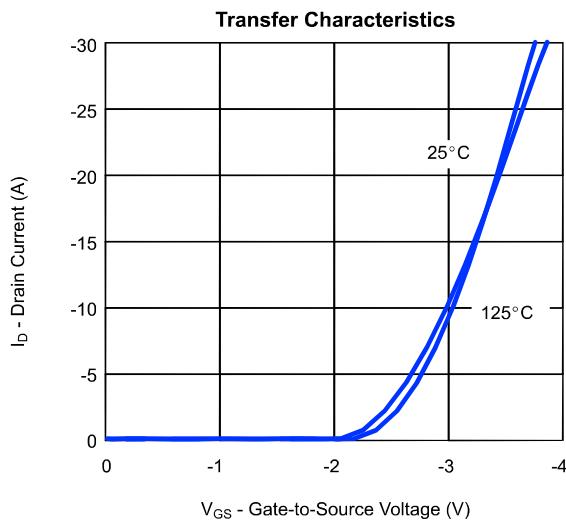
Electrical Characteristics ($T_A = 25^\circ C$ Unless Otherwise Specified)

Symbol	Parameter	Limit	Min	Typ	Max	Unit
STATIC						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=-250 \mu A$	-1	-1.4	-3	V
I_{GSS}	Gate Leakage Current	$V_{DS}=0V$, $V_{GS}=\pm 20V$			± 100	nA
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-30V$, $V_{GS}=0V$			-1	μA
		$V_{DS}=-30V$, $V_{GS}=0V$ $T_J=55^\circ C$			-25	
$I_{D(ON)}$	On-State Drain Current ^a	$V_{DS}=-5V$, $V_{GS}=-10V$	-30			A
$R_{DS(ON)}$	Drain-Source On-State Resistance ^a	$V_{GS}=-10V$, $I_D=-9.1A$		15	20	$m\Omega$
		$V_{GS}=-4.5V$, $I_D=-6.9A$		25	35	
V_{SD}	Diode Forward Voltage	$I_S=-2.1A$, $V_{GS}=0V$		-0.8	-1.2	V
DYNAMIC						
Q_g	Total Gate Charge	$V_{DS}=-15V$, $V_{GS}=-10V$, $I_D=-9.1A$		38	45	nC
Q_{gs}	Gate-Source Charge			7.7		
Q_{gd}	Gate-Drain Charge			9		
R_g	Gate Resistance	$V_{GS}=0V$, $V_{DS}=0V$, $f=1MHz$		5.5		Ω
C_{iss}	Input capacitance	$V_{DS}=-15V$, $V_{GS}=0V$, $f=1MHz$		1730	1900	pF
C_{oss}	Output Capacitance			240		
C_{rss}	Reverse Transfer Capacitance			70		
$t_{d(on)}$	Turn-On Delay Time	$V_{DD}=-15V$, $R_L=15\Omega$ $I_D=-1A$, $V_{GEN}=-10V$ $R_G=6\Omega$		41	50	ns
t_r	Turn-On Rise Time			19	23	
$t_{d(off)}$	Turn-Off Delay Time			105	120	
t_f	Turn-On Fall Time			17	20	

Notes: a. Pulse test; pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$

P-Channel 30-V (D-S) MOSFET

Typical Characteristics ($T_J = 25^\circ\text{C}$ Noted)

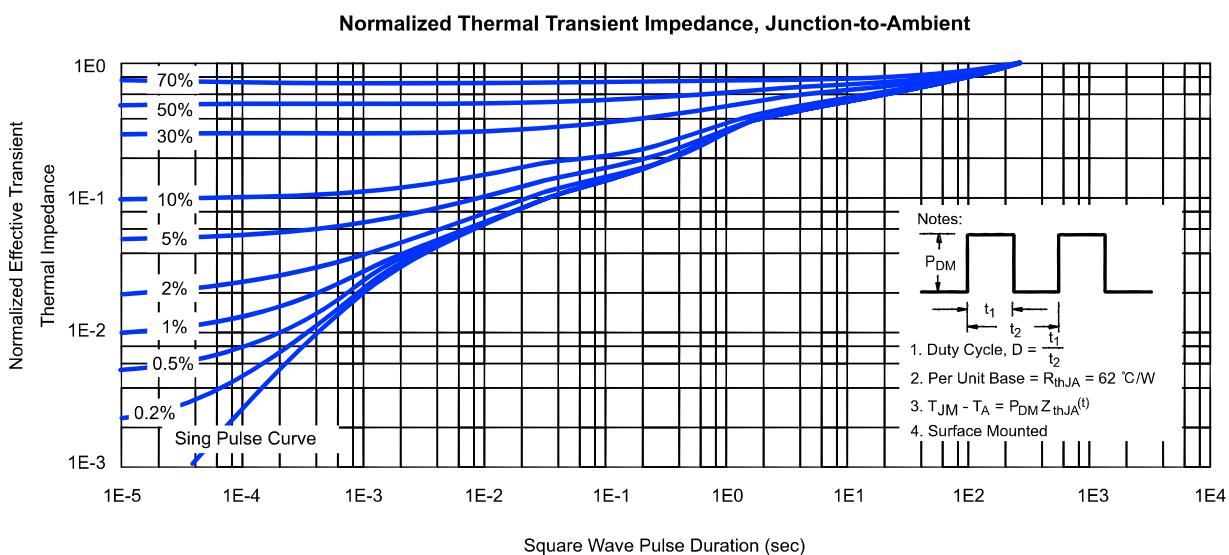
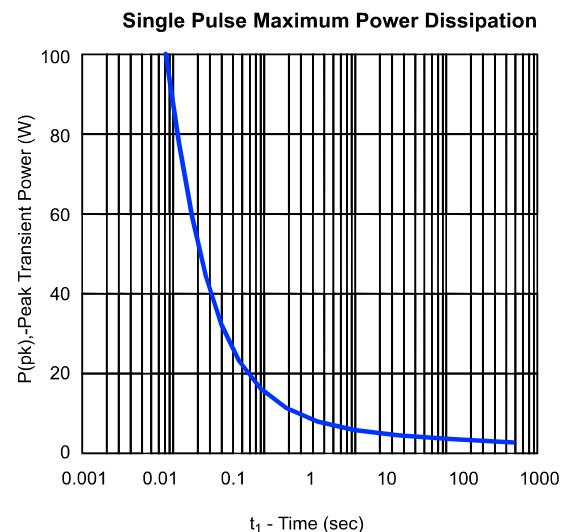
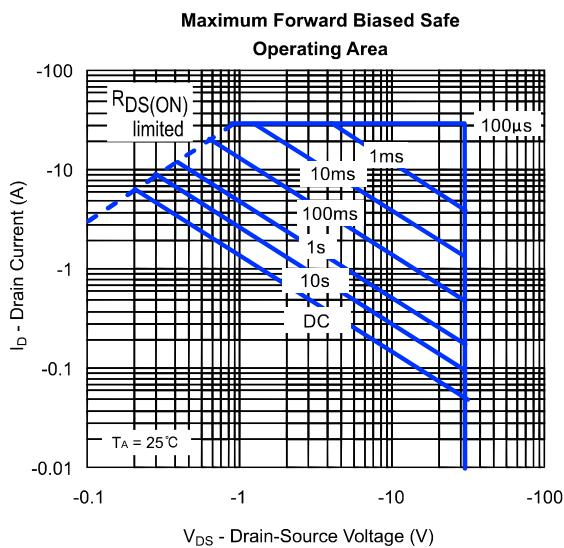
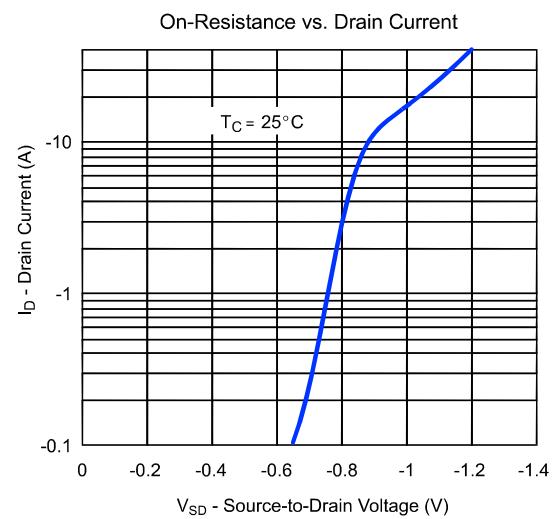
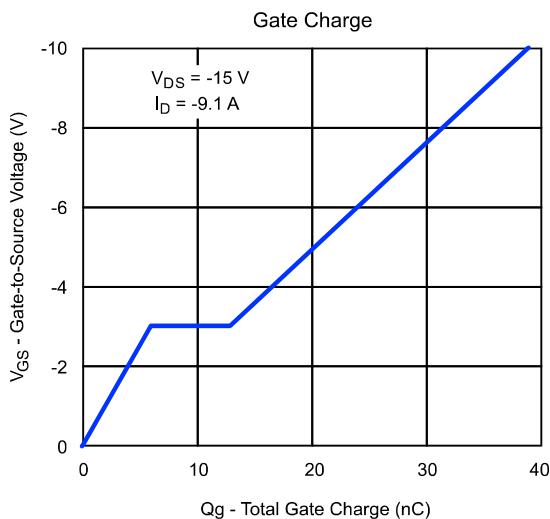


Typical Characteristics ($T_J = 25^\circ\text{C}$ Noted)

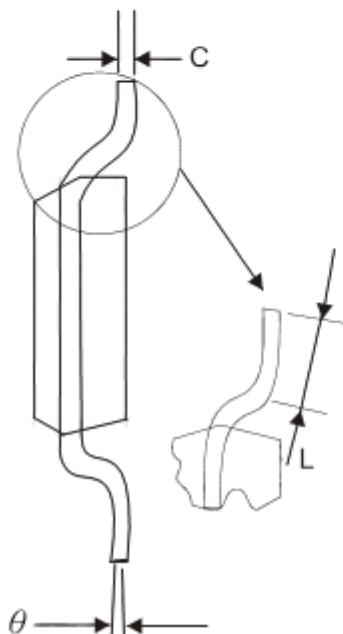
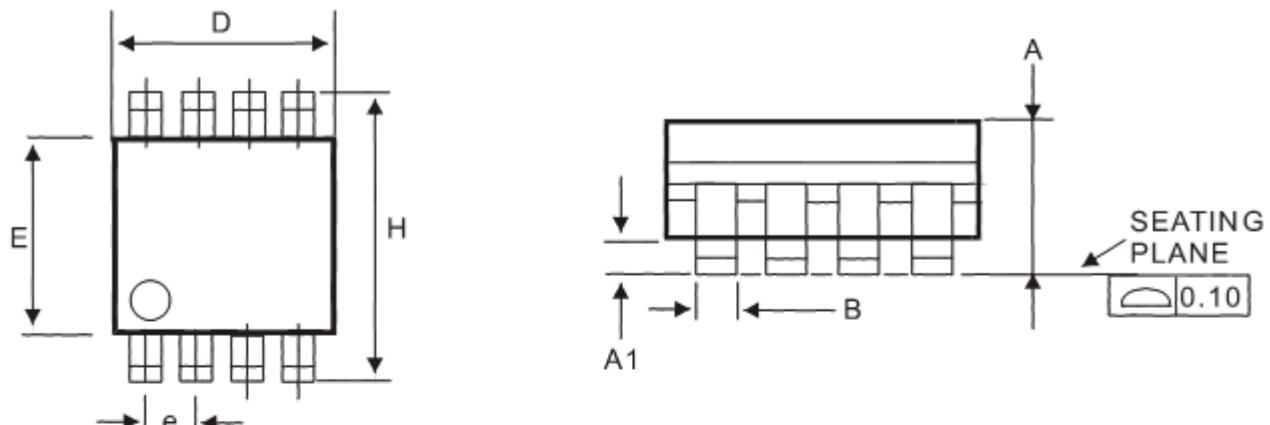


Matsuki Electric

P-Channel 30-V (D-S) MOSFET



SOP-8 Package Outline



DIM	MILLIMETERS (mm)	
	MIN	MAX
A	1.35	1.75
A1	0.10	0.25
B	0.35	0.49
C	0.18	0.25
D	4.80	5.00
E	3.80	4.00
e	1.27 BSC	
H	5.80	6.20
L	0.40	1.25
θ	0°	7°

Note: 1. Refer to JEDEC MS-012AA.

2. Dimension "D" does not include mold flash, protrusions or gate burrs . Mold flash, protrusions or gate burrs shall not exceed 0.15 mm per side.